

Search Notes**Application/Control No.**

10/821,798

Examiner

Paul D. Kim

Applicant(s)/Patent under Reexamination

FRANOSCH ET AL.

Art Unit

3729

SEARCHED

Class	Subclass	Date	Examiner
29	417 592.1 602.1 856 858 883 885	9/27/2006	PK
73	159 204.11		
	204.17		
	204.26 721		
156	268 344 643		
427	249 258		
	402 404		
438	455 458 976		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Text Search EAST/NPL (IEEE)	9/27/2006	PK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner